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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.
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09/148,392 09/04/98 BAEZ

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EXAMINER

LMC1/0912

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ART UNIT

PAPER NUMBER

2763

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Please find below and/or attached an Office communication concerning this application or proceeding.

Commissioner of Patents and Trademarks

Office Action Summary

Application No.
09/148,392

Applicant(s)

Baez

Examiner
William Thomson

Group Art Unit
2763



☒ Responsive to communication(s) filed on Jun 21, 2000

☒ This action is **FINAL**.

☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11; 453 O.G. 213.

A shortened statutory period for response to this action is set to expire 3 month(s), or thirty days, whichever is longer, from the mailing date of this communication. Failure to respond within the period for response will cause the application to become abandoned. (35 U.S.C. § 133). Extensions of time may be obtained under the provisions of 37 CFR 1.136(a).

Disposition of Claims

☒ Claim(s) 1-27 is/are pending in the application.

Of the above, claim(s) _____ is/are withdrawn from consideration.

☐ Claim(s) _____ is/are allowed.

☒ Claim(s) 1-27 is/are rejected.

☐ Claim(s) _____ is/are objected to.

☐ Claims _____ are subject to restriction or election requirement.

Application Papers

☐ See the attached Notice of Draftsperson's Patent Drawing Review, PTO-948.

☐ The drawing(s) filed on _____ is/are objected to by the Examiner.

☐ The proposed drawing correction, filed on _____ is ☐ approved ☐ disapproved.

☐ The specification is objected to by the Examiner.

☐ The oath or declaration is objected to by the Examiner.

Priority under 35 U.S.C. § 119

☐ Acknowledgement is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d).

☐ All ☐ Some* ☐ None of the CERTIFIED copies of the priority documents have been received.

☐ received in Application No. (Series Code/Serial Number) _____

☐ received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

*Certified copies not received: _____

☐ Acknowledgement is made of a claim for domestic priority under 35 U.S.C. § 119(e).

Attachment(s)

☐ Notice of References Cited, PTO-892

☐ Information Disclosure Statement(s), PTO-1449, Paper No(s). _____

☐ Interview Summary, PTO-413

☐ Notice of Draftsperson's Patent Drawing Review, PTO-948

☐ Notice of Informal Patent Application, PTO-152

--- SEE OFFICE ACTION ON THE FOLLOWING PAGES ---

Art Unit: 2763

DETAILED ACTION

1. Claims 1-27 have been submitted for examination. Claims 1, 11, 21 and 22 have been amended. Claims 1-27 have been examined and rejected. THIS ACTION IS MADE FINAL.

TITLE

2. The title of the invention is not descriptive. A new title is required that is clearly indicative of the invention to which the claims are directed. The title is of a generic nature drawn to a family of systems and not to the applicant's specific invention. **Amendment to the title has been entered, yet does not remedy the deficiency.**

ABSTRACT

3. Applicant is reminded of the proper content of an abstract of the disclosure.

A patent abstract is a concise statement of the technical disclosure of the patent and *should include that which is new in the art to which the invention pertains*. If the patent is of a basic nature, the entire technical disclosure may be new in the art, and the abstract should be directed to the entire disclosure. If the patent is in the nature of an improvement in an old apparatus, process, product, or composition, *the abstract should include the technical disclosure of the improvement*. In certain patents, particularly those for compounds and compositions, wherein the process for making and/or the use thereof are not obvious, the abstract should set forth a process for making and/or use thereof. *If the new technical disclosure involves modifications or alternatives, the abstract should mention by way of example the preferred modification or alternative*. **Applicant's amendment does not remedy the deficiency. The abstract does not recite the novelty of the invention.**

Art Unit: 2763

Double Patenting

4. Claims 1-27 are provisionally rejected under 35 U.S.C. 101 as claiming the same invention as that of claims 1-30 of copending Application No. 09/474,008. This is a provisional double patenting rejection since the conflicting claims have not in fact been patented. Examiner reiterates that this is a **provisional** double patenting rejection and as yet the claims recited within each interrelated case have not been brought to fruition. Therefore, until all matters are resolved and there appears to be allowable subject matter not claimed in both applications, this rejection will stand.

Claim Interpretation and Definitions

5. The examiner has given the broadest reasonable interpretation to the Applicant's claim language. As such, Examiner is providing a number of terms as defined in the art and used to interpret Applicant's claim language. Examiner is interpreting the following terms in light of the Applicant's specification and the well known definitions of the prior art teachings. Examiner has used Applicant's own definitions to provide a basis for the relevance of specific rejected limitations in view of prior art know made of record.

Parameter Function. Describes the variation of one parameter as a function of another parameter. Each circuit is characterized by a parameter function. The relationship between the design constraints and the optimizing parameters. *Applicant's specification*

Art Unit: 2763

Design Constraints: A constraint set including constraint parameters which are parameters that must be met. A **constraint parameter** is the propagation delay and an **optimizing parameter** is the power consumption. Alternately the propagation delay is the optimizing parameter and the power consumption is the constraint parameter. *Applicant's specification*

Preamble of the Claims

The preamble of the claims presented for examination have not been given patentable weight. Examiner notes the Applicant's have amended an addition phrase "comprising" into the claims. Appropriate weight is given to limitations recited in the body of the claim that are needed for the purpose of antecedence. "A mere statement of purpose or intended use in the preamble of a claim need not be considered in finding anticipation; however, it must be considered if the language of a preamble is necessary to give meaning to the claim" *Diversitech Corp. v. Century Steps, Inc.*, 7 USPQ2d 1315 (Fed. Cir. 1988); *In re Stencel*, 4 USPQ2d 1071 (Fed. Cir. 1987)

Response to Arguments

6. Applicant's arguments filed June 21, 2000 have been fully considered. Applicant's arguments with respect to claims 1-27 have been considered. This response has been necessitated by Applicant's amendments. Applicant's arguments regarding Sarin and Jyu et al. and Roethig(145) and Breid are not persuasive and the prior art rejection directed to claims 1-27 stands.

Art Unit: 2763

Specific Response to Arguments and Amendments

Applicant has primarily argued:

Sari, Jyu, Roethig, and Breid taken alone or in any combination, do not disclose, suggest, or render obvious create parameter functions for the plurality of circuits in the subsystem, the subsystem having design constraints, each one of the parameter functions corresponding to each one of the circuits.

Unfortunately, all the prior art citations specifically disclose the use of the same methodology as Applicant's have claimed as novel. Sarin and Jyu et al. and Roethig(145) and Breid teach the optimizing and modeling approach. Applicants failed to claim the operational and function differences for optimizing the circuit design and therefore the claims are encompassed by the teachings within Sarin and Jyu et al. and Roethig(145) and Breid. Specifically, Sarin and Jyu et al. and Roethig(145) and Breid explicitly teach a **constraint parameter** that is the propagation delay and an **optimizing parameter** that is the power consumption. Alternately the propagation delay is the optimizing parameter and the power consumption is the constraint parameter. Further, these relationships are represented in a parameter function that associates the two (or more) parameters for optimizing the circuit(s). Subsystems are transistors in a gate array or sub combinations of the circuits within a larger circuit with interrelated parameters for design, simulation and optimizations. .

Art Unit: 2763

Furthermore, Applicants' arguments amount to a general allegation that the claims define a patentable invention without specifically pointing out how the language of the claims patentably distinguishes them from the references. Though an attempt at determining a distinction was proffered, the citation was not meaningful. Applicants have responded by selective interpretation and selective viewing without providing a proper analysis as to the points of distinction. Sarin and Jyu et al. and Roethig(145) and Breid provide for the re-designing and optimizing of designs for multiple circuit models and characteristics.

Moreover, Applicant's arguments do not clearly point out the patentable novelty which he or she thinks the claims present in view of the state of the art disclosed by the references cited. Applicant's have not provided *any* effective argument as to any limitations that might be within their application and that might be distinguishable over the prior art teachings of the Sarin and Jyu et al. and Roethig(145) and Breid. Applicant's invention, as claimed, is clearly anticipated by the entire teaching of Sarin and Jyu et al. and Roethig(145) and Breid and the prior art of record.

Applicant is solving the same problem with the same technology in the same manner as Sarin and Jyu et al. and Roethig(145) and Breid. There is no inventive step when all that is claimed is that which is well known and inherent in the prior art teachings. Applicant's invention and Sarin and Jyu et al. and Roethig(145) and Breid perform the same functions and operations with the same equipment. Both products allow users to design, model, simulate and optimize based on parameter function corresponding to each circuit with iterative operations.

Art Unit: 2763

Applicant has not provided any effective argument as to any patentable distinction, improvement or unexpected result that might occur over the prior art teachings when Applicant's method of handling modeling and optimizing for circuits than that which is built into the Sarin and Jyu et al. and Roethig(145) and Breid. Applicants are using the well known methodology to effect designs within a circuit framework. The engineer using a simulation-modeler-Optimizer will always have design constraints built into the model. This includes setting two parameters against one another to yield operational constraints that are used to optimize the layout. This is merely using the well known tool of the trade for its specific purpose. The courts have held that "A reference anticipates a claim if it discloses the claimed invention such that a skilled artisan could take its teachings in combination with his own knowledge of the particular art and be in possession of the invention." *In re Graves*, 36 USPQ2d 1697 (Fed. Cir. 1995); *In re Sase*, 207 USPQ 107 (CCPA 1980); *In re Samour*, 197 USPQ 1 (CCPA 1978).

Applicant is currently claiming a system which uses timing or propagation delays and power parameters to optimize transistor sizing. The relationships between these two parameters and the sizing of a circuit are well known in the art. The use of a computer system to optimize the layout and sizing of the circuit based on these parameters is just as old in the art. Graphical and curve trace methodologies for optimizations that cover applicant's claimed invention go back for many years.

Art Unit: 2763

Claim Rejections - 35 U.S.C. § 102

7. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless --

(a) the invention was known or used by others in this country, or patented or described in a printed publication in this or a foreign country, before the invention thereof by the applicant for a patent.

(b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.

(e) the invention was described in a patent granted on an application for patent by another filed in the United States before the invention thereof by the applicant for patent, or on an international application by another who has fulfilled the requirements of paragraphs (1), (2), and (4) of section 371(c) of this title before the invention thereof by the applicant for patent.

8. Claims 1-27 are rejected under 35 U.S.C. 102(e) as being clearly anticipated by Sarin or Jyu et al. or Jones et al. (288) or Roethig (145) and rejected under 102(a) as being clearly anticipated by Roethig(145) and rejected under 102(b) as being clearly anticipated by Breid.

Taking claim 1, for example, Sarin and Jyu et al. and Jones et al. (288) and Roethig(145) and Breid disclose:

(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

Art Unit: 2763

A method for determining optimal values of design parameters of a subsystem comprising a plurality of circuits, the method comprising:

creating parameter functions for a plurality of circuits in a subsystem, the subsystem having design constraints, each one of the parameter functions corresponding to each one of the circuits, the corresponding circuits, the parameter functions representing a relationship among the design parameters; and

optimizing design parameters based on the parameter functions to satisfy the design constraints.

As to claim 2, the method of claim 1, wherein the creating the parameter functions comprises:

configuring each circuit of the plurality of circuits and generating values of design parameters for each circuit according to the configuration circuit, the values providing the parameter functions are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid. (Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6,

Art Unit: 2763

5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 3, the method of claim 2, wherein the design parameters include constraint and optimizing sets, the constraint set including constraint parameters having values selectable to meet the design constraints, the optimizing set including optimizing parameters having values to be optimized are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig(145) and Breid. (Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 4, the method of claim 3, wherein optimizing comprises:

selecting values of the constraint parameters to meet the design constraints;

determining values of the optimizing parameters corresponding to the selected values of the constraint parameters based on the parameter functions; and

Art Unit: 2763

iterating the selection of values and determining of values steps until values of the optimizing parameters are within a predetermined optimal range are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig(145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 5, the method of claim 3, wherein the constraint parameters include a delay parameter and the optimizing parameters include a power parameter are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines

Art Unit: 2763

28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 6, the method of claim 5, wherein the design constraints include a delay constraint are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 7, the method of claim 6, wherein the step of configuring each circuit of the plurality of circuits includes sizing components in each circuit is disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in

Art Unit: 2763

figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 8, the method of claim 6, wherein the step of configuring each circuit of the plurality of circuits includes selecting a design technology for each circuit, the design technology being one of static and dynamic technologies is disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 9, the method of claim 7, wherein the generating values of design parameters for each circuit according to the configured circuit, the values providing the parameter functions including generating a circuit netlist representing the configured circuit;

generating a timing file based on the circuit netlist using a circuit critical path;

Art Unit: 2763

calculating timing values by using a timing simulator; and

calculating power values by using a power estimator is disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As to claim 10, the method of claim 8, wherein optimizing comprises:

selecting values of the delay parameter within the delay constraint;

determining values of the power parameter corresponding to the selected values of the delay parameter based on the parameter function; and

iterating the steps of selecting values and determining values until values of the power parameter are within a predetermined optimal range are disclosed throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B,

Art Unit: 2763

circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

As for claims 11-27 are rejected for the same reasoning as claims 1-10, set forth above, supra. Claims 11-27 are equivalent machine readable medium having embodied a computer program for processing by a machine and system claims containing the same limitations and variations of limitations as recited in method claims 1-10 and taught throughout Sarin and Jyu et al. and Jones et al. (288) and Roethig (145) and Breid.(Sarin: Abstract, Figures 1-4, 7, 8, 10, 11, 12, col. 2, lines 14 et seq., col. 4, lines 21 et seq., , Verilog and Powergate; Breid: Abstract, Figures 2-4, flowcharts in figures 5 and 6, col. 6, lines 20 et seq.; Jyu et al.: Abstract, Figures 3, 4A-4B, circuit areas 500 and 502, flowcharts in figures 6, 6A-6E, note power/transistor parameter records 702 and 704, 706 and 708, see figure 7C, 8-10, flowcharts in figures 11A and 11B, 11C-15 (code), 16-24, region of interest in figure 25, figure 26, figures 27 and 28, col. 6, lines 6 et seq., design goals, col. 10, lines 52 et seq., POWERMILL, col. 18, lines 28 et seq.; Roethig: Abstract, Figures 4, 6, 5, 7A & 7B, 9, 10, 11, 12, 13, 16-18, col. 4, lines 42 et seq.; Jones et al.: Abstract, Figures 3, 4 and 5, col. 3, lines 29 et seq.)

Art Unit: 2763

9. THIS ACTION IS MADE FINAL. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP § 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A SHORTENED STATUTORY PERIOD FOR REPLY TO THIS FINAL ACTION IS SET TO EXPIRE THREE MONTHS FROM THE MAILING DATE OF THIS ACTION. IN THE EVENT A FIRST REPLY IS FILED WITHIN TWO MONTHS OF THE MAILING DATE OF THIS FINAL ACTION AND THE ADVISORY ACTION IS NOT MAILED UNTIL AFTER THE END OF THE THREE-MONTH SHORTENED STATUTORY PERIOD, THEN THE SHORTENED STATUTORY PERIOD WILL EXPIRE ON THE DATE THE ADVISORY ACTION IS MAILED, AND ANY EXTENSION FEE PURSUANT TO 37 CFR 1.136(A) WILL BE CALCULATED FROM THE MAILING DATE OF THE ADVISORY ACTION. IN NO EVENT, HOWEVER, WILL THE STATUTORY PERIOD FOR REPLY EXPIRE LATER THAN SIX MONTHS FROM THE DATE OF THIS FINAL ACTION.

Art Unit: 2763

10. Any inquiry concerning this communication or earlier communications from the examiner should be directed to William Thomson whose telephone number is (703) 305-0022. The examiner can be usually reached between 9:30 a.m. - 4:00 p.m. Monday thru Friday. Voice mail is checked throughout the day. Please leave a detailed message.

If attempts to reach the Examiner by telephone are unsuccessful, the Examiner's supervisor, Mr. Kevin Teska, can be reached on 704-305-9704. The fax phone number for this Group is 703-308-1396.

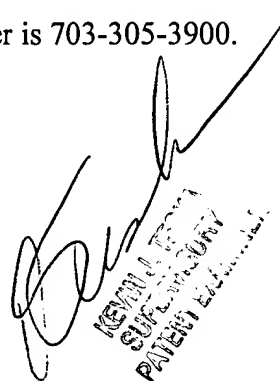
Any inquiry of a general nature or relating to the status of this application should be directed to the Group receptionist whose telephone number is 703-305-3900.

William D. Thomson

Patent Examiner

A.U. 2763

September 7, 2000



Handwritten signature of Kevin Teska, Supervisor, Patent Examiner. Below the signature is a stamp that reads: "KEVIN TESKA", "SUPERVISOR", "PATENT EXAMINER".